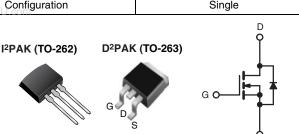
COMPLIANT

Power MOSFET

| PRODUCT SUMMARY | | | | |
|---------------------------------|------------------------|-----|--|--|
| V _{DS} (V) | 600 | | | |
| $R_{DS(on)}\left(\Omega\right)$ | V _{GS} = 10 V | 4.4 | | |
| Q _g (Max.) (nC) | 18 | | | |
| Q _{gs} (nC) | 3.0 | | | |
| Q _{gd} (nC) | 8.9 | | | |
| Configuration | Single | | | |



N-Channel MOSFET

FEATURES

- Surface Mount (IRFBC20S/SiHFBC20S)
- Low-Profile Through-Hole (IRFBC20L/SiHFBC20L)
- Available in Tape and Reel (IRFBC20S/SiHFBC20S)
- · Dynamic dV/dt Rating
- 150 °C Operating Temperature
- Fast Switching
- · Fully Avalanche Rated
- · Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The D²PAK is a surface mount power package capable of the accommodating die sizes up to HEX-4. It provides the highest power capability and the lowest possible on-resistance in any existing surface mount package. The D²PAK is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0 W in a typical surface mount application. The through-hole version (IRFBC20L/SiHFBC20L) is a available for low-profile applications.

| ORDERING INFORMATION | | | | |
|----------------------|-----------------------------|-----------------------------|-----------------------------|--|
| Package | D ² PAK (TO-263) | D ² PAK (TO-263) | I ² PAK (TO-262) | |
| Lead (Pb)-free | IRFBC20SPbF | IRFBC20STRLPbFa | IRFBC20LPbF | |
| | SiHFBC20S-E3 | SiHFBC20STL-E3a | SiHFBC20L-E3 | |
| SnPb | IRFBC20S | IRFBC20STRL ^a | IRFBC20L | |
| | SiHFBC20S | SiHFBC20STL ^a | SiHFBC20L | |

Note

a. See device orientation.

| PARAMETER | | | SYMBOL | LIMIT | UNIT | |
|--|-------------------------|-----------------------------------|------------------|------------------|------|--|
| Drain-Source Voltage | | | V_{DS} | 600 | V | |
| Gate-Source Voltage | | | V_{GS} | ± 20 | V | |
| Continuous Drain Current ^e | V _{GS} at 10 V | T _C = 25 °C | - I _D | 2.2 | | |
| | VGS at 10 V | $T_C = 100 ^{\circ}C$ | | 1.4 | Α | |
| Pulsed Drain Current ^{a, e} | | | I _{DM} | 8.0 | | |
| Linear Derating Factor | | | | 0.40 | W/°C | |
| Single Pulse Avalanche Energy ^{b, e} | | | E _{AS} | 84 | mJ | |
| Avalanche Current ^a | | | I _{AR} | 2.2 | Α | |
| Repetiitive Avalanche Energy ^a | | | E _{AR} | 5.0 | mJ | |
| Maximum Power Dissipation | T _A = 2 | T _A = 25 °C | | 3.1 | W | |
| | $T_C = 2$ | 25 °C | P_{D} | 50 | ** | |
| Peak Diode Recovery dV/dt ^{c, e} | | dV/dt | 3.0 | V/ns | | |
| Operating Junction and Storage Temperature Range | | T _J , T _{stg} | - 55 to + 150 | °C | | |
| Soldering Recommendations (Peak Tempera | ture) for 10 | for 10 s | | 300 ^d |] | |

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \,^{\circ}\text{C}$, $L = 31 \,^{\circ}\text{mH}$, $R_G = 25 \,^{\circ}\Omega$, $I_{AS} = 2.2 \,^{\circ}\Lambda$ (see fig. 12).
- c. $I_{SD} \le 2.2$ A, $dI/dt \le 40$ A/µs, $V_{DD} \le V_{DS}$, $T_{J} \le 150$ °C.
- d. 1.6 mm from case.
- e. Uses IRFBC20/SiHFBC20 data and test conditions.
- * Pb containing terminations are not RoHS compliant, exemptions may apply

IRFBC20S, SiHFBC20S, IRFBC20L, SiHFBC20L

Vishay Siliconix



| THERMAL RESISTANCE RATINGS | | | | | |
|--|-------------------|------|------|------|--|
| PARAMETER | SYMBOL | TYP. | MAX. | UNIT | |
| Maximum Junction-to-Ambient (PCB Mounted, steady-state) ^a | R _{thJA} | - | 40 | °C/W | |
| Maximum Junction-to-Case (Drain) | R _{thJC} | - | 2.5 | | |

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

| SPECIFICATIONS $T_J = 25 ^{\circ}\text{C}$, | | wise noted | | | T | | 1 |
|--|-----------------------|---|--|-----------|------------------------|------------------|------|
| PARAMETER | SYMBOL | TEST CONDITIONS | | MIN. | TYP. | MAX. | UNIT |
| Static | | | | | | | |
| Drain-Source Breakdown Voltage | V_{DS} | V _{GS} : | $V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$ | | - | - | V |
| V _{DS} Temperature Coefficient | $\Delta V_{DS}/T_{J}$ | Referenc | Reference to 25 °C, I _D = 1 mA ^c | | 0.88 | - | V/°C |
| Gate-Source Threshold Voltage | V _{GS(th)} | V _{DS} = | $V_{DS} = V_{GS}, I_{D} = 250 \mu A$ | | - | 4.0 | V |
| Gate-Source Leakage | I _{GSS} | , | V _{GS} = ± 20 V | - | - | ± 100 | nA |
| Zoro Coto Voltago Drain Current | 1 | $V_{DS} = 600 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 480 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125 ^{\circ}\text{C}$ | | - | - | 100 | μΑ |
| Zero Gate Voltage Drain Current | I _{DSS} | | | - | - | 500 | |
| Drain-Source On-State Resistance | R _{DS(on)} | V _{GS} = 10 V | | | - | 4.4 | Ω |
| Forward Transconductance | 9 _{fs} | V _{DS} = 50 V, I _D = 1.3 A ^c | | 1.4 | - | - | S |
| Dynamic | | | | | | | • |
| Input Capacitance | C _{iss} | $V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz}, \text{ see fig. } 5^{\text{c}}$ | | - | 350 | - | pF |
| Output Capacitance | C _{oss} | | | - | 48 | - | |
| Reverse Transfer Capacitance | C _{rss} | | | - | 8.6 | - | |
| Total Gate Charge | Qg | | | - | - | 18 | nC |
| Gate-Source Charge | Q _{gs} | V _{GS} = 10 V | $I_D = 2.0 \text{ A}, V_{DS} = 360 \text{ V},$ see fig. 6 and $13^{b, c}$ | - | - | 3.0 | |
| Gate-Drain Charge | Q _{gd} | | See lig. 0 and 13 | - | - | 8.9 | |
| Turn-On Delay Time | t _{d(on)} | | | - | 10 | - | - ns |
| Rise Time | t _r | | V 200 V I 20 A | | 23 | - | |
| Turn-Off Delay Time | t _{d(off)} | $V_{DD} = 300 \text{ V}, I_D = 2.0 \text{ A},$ $R_G = 18 \Omega, R_D = 150 \Omega, \text{ see fig. } 10^{b, \text{ c}}$ | | - | 30 | - | |
| Fall Time | t _f | | | - | 25 | - | |
| Internal Source Inductance | L _S | Between lead, and center of die contact | | - | 7.5 | - | nΗ |
| Drain-Source Body Diode Characteristic | s | | | | | • | • |
| Continuous Source-Drain Diode Current | I _S | MOSFET sym showing the | MOSFET symbol showing the | | - | 2.2 | Α |
| Pulsed Diode Forward Current ^a | I _{SM} | integral reverse p - n junction diode | | - | - | 8.0 | |
| Body Diode Voltage | V _{SD} | $T_J = 25 ^{\circ}\text{C}, I_S = 2.2 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$ | | - | - | 1.6 | V |
| Body Diode Reverse Recovery Time | t _{rr} | T _J = 25 °C, I _F = 2.0 A, dI/dt = 100 A/μs ^{b, c} | | - | 290 | 580 | ns |
| Body Diode Reverse Recovery Charge | Q _{rr} | | | - | 0.67 | 1.3 | μС |
| Forward Turn-On Time | t _{on} | Intrinsic tu | on is don | ninated b | y L _S and I | _ _D) | |

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 µs; duty cycle \leq 2 %. c. Uses IRFBC20/SiHFBC20 data and test conditions.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

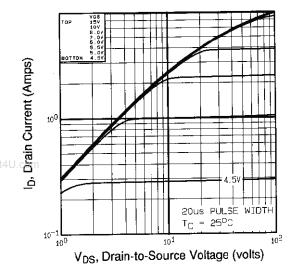


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

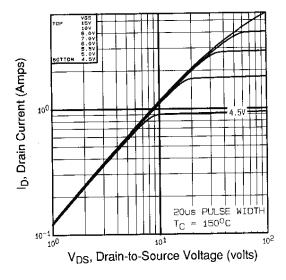


Fig. 2 - Typical Output Characteristics, T_{C} = 150 $^{\circ}C$

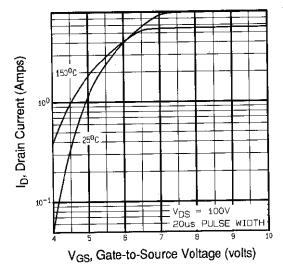


Fig. 3 - Typical Transfer Characteristics

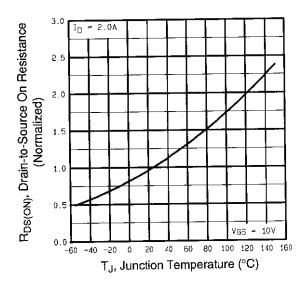


Fig. 4 - Normalized On-Resistance vs. Temperature

IRFBC20S, SiHFBC20S, IRFBC20L, SiHFBC20L

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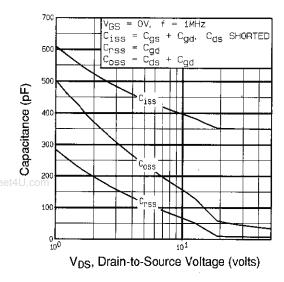


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

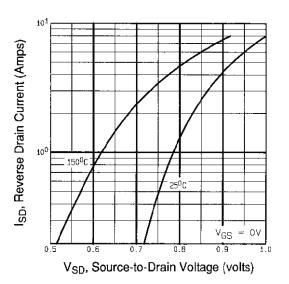


Fig. 7 - Typical Source-Drain Diode Forward Voltage

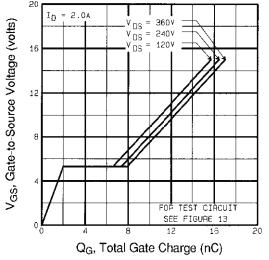


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

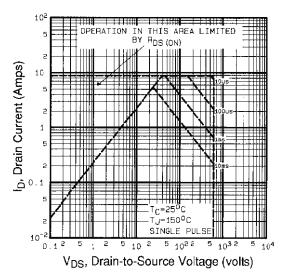


Fig. 8 - Maximum Safe Operating Area

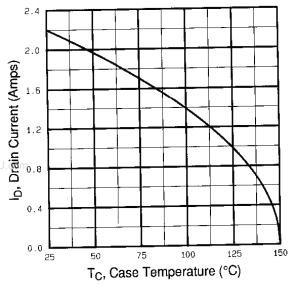


Fig. 9 - Maximum Drain Current vs. Case Temperature

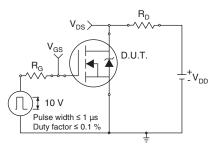


Fig. 10a - Switching Time Test Circuit

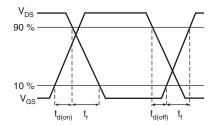


Fig. 10b - Switching Time Waveforms

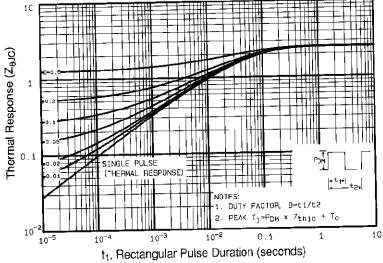


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

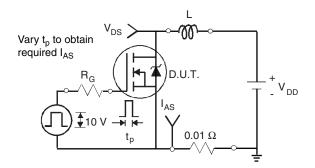


Fig. 12a - Unclamped Inductive Test Circuit

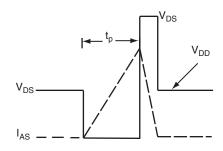


Fig. 12b - Unclamped Inductive Waveforms

IRFBC20S, SiHFBC20S, IRFBC20L, SiHFBC20L

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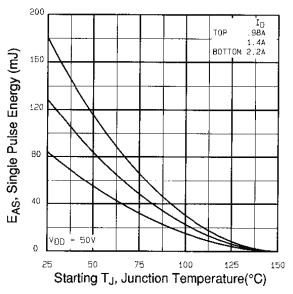


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

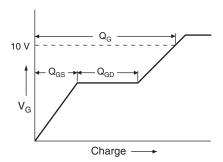


Fig. 13a - Maximum Avalanche Energy vs. Drain Current

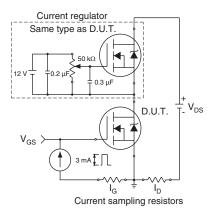
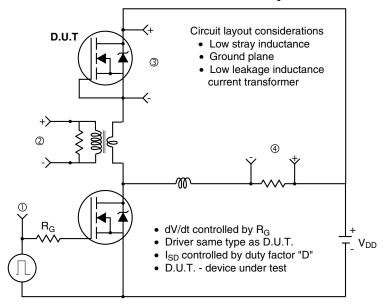


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



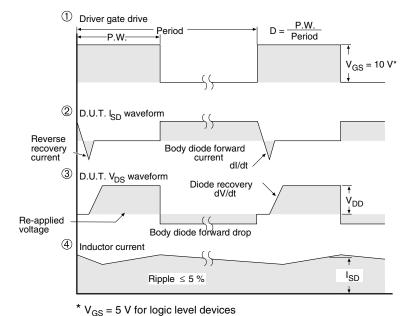


Fig. 14 - For N-Channel

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